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Thermal boundary conductance across heteroepitaxially grown ZnO/GaN interfaces



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Thermal Boundary Conductance Across Heteroepitaxial ZnO/GaN Interfaces: Assessment of the Phonon Gas Model

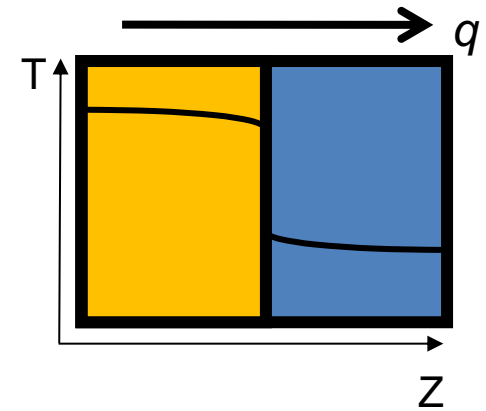
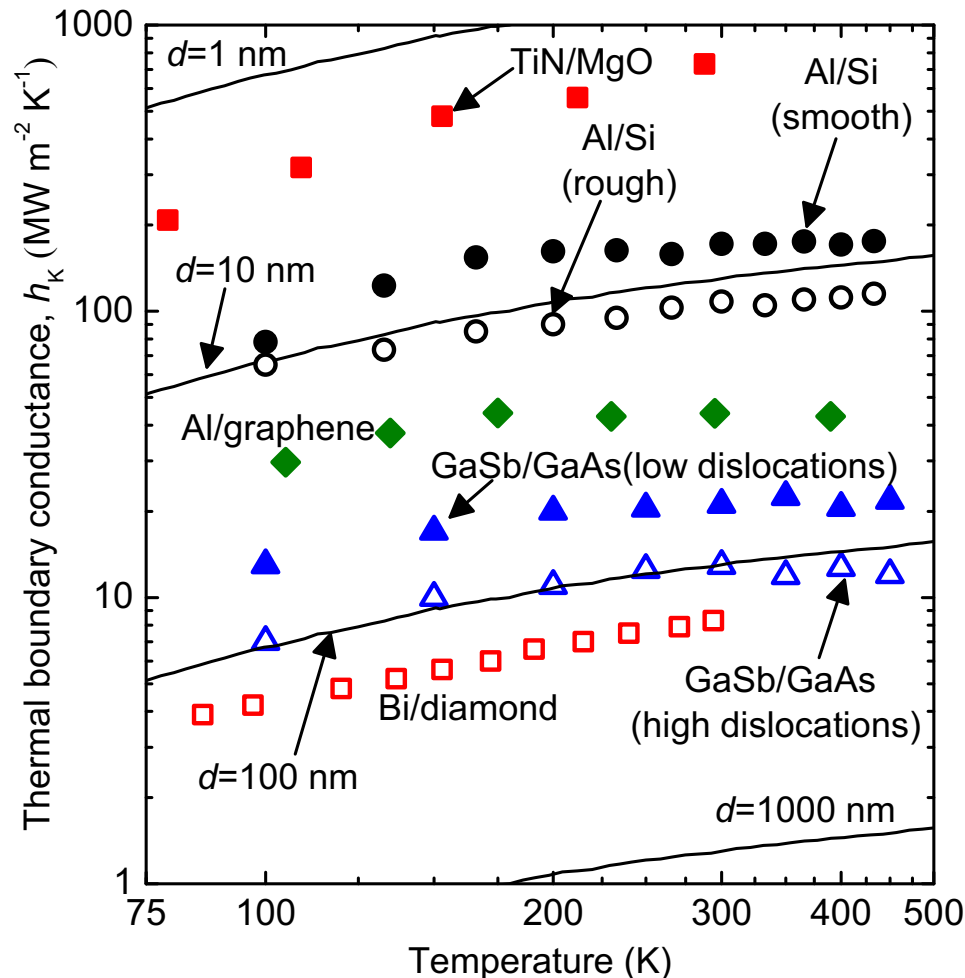
John T. Gaskins,[†] George Kotsonis,[‡] Ashutosh Giri,[§] Shenghong Ju,^{||,⊥} Andrew Rohskopf,[#] Yekan Wang,[▽] Tingyu Bai,[▽] Edward Sachet,[‡] Christopher T. Shelton,[‡] Zeyu Liu,[○] Zhe Cheng,[#] Brian M. Foley,[#] Samuel Graham,^{#,◆} Tengfei Luo,^{○,¶} Asegun Henry,^{#,◆,■} Mark S. Goorsky,[▽] Junichiro Shiomi,^{||,⊥} Jon-Paul Maria,[‡] and Patrick E. Hopkins^{*,§,▲,▽}

Dr. John Gaskins
Principle Scientist
UVA

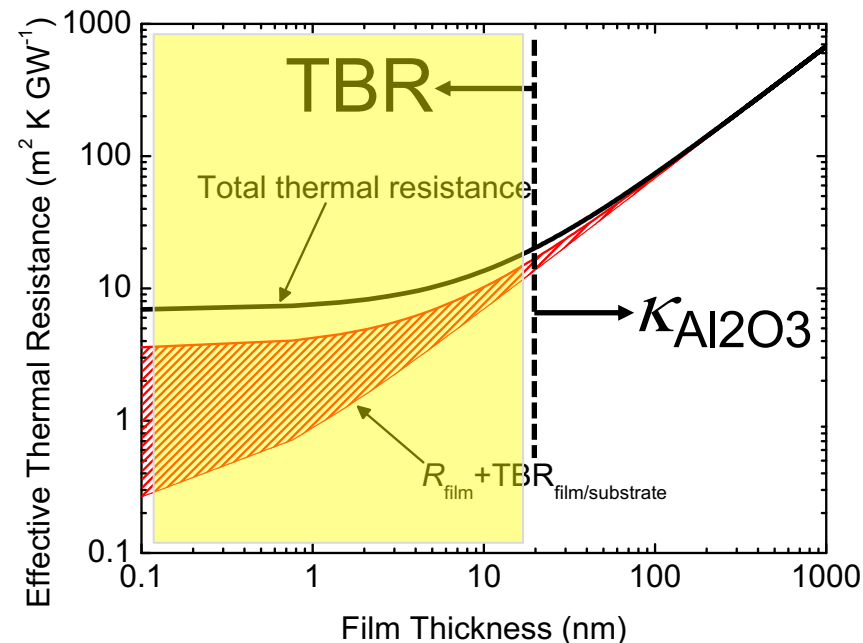


Thermal boundary conductance – nanoscale resistances

$$q = h_K \Delta T = \frac{1}{R_K} \Delta T$$



Ex: Al/ALD Al_2O_3 /Si



Scott *et al.* *APL Materials*
6, 058302 (2018)

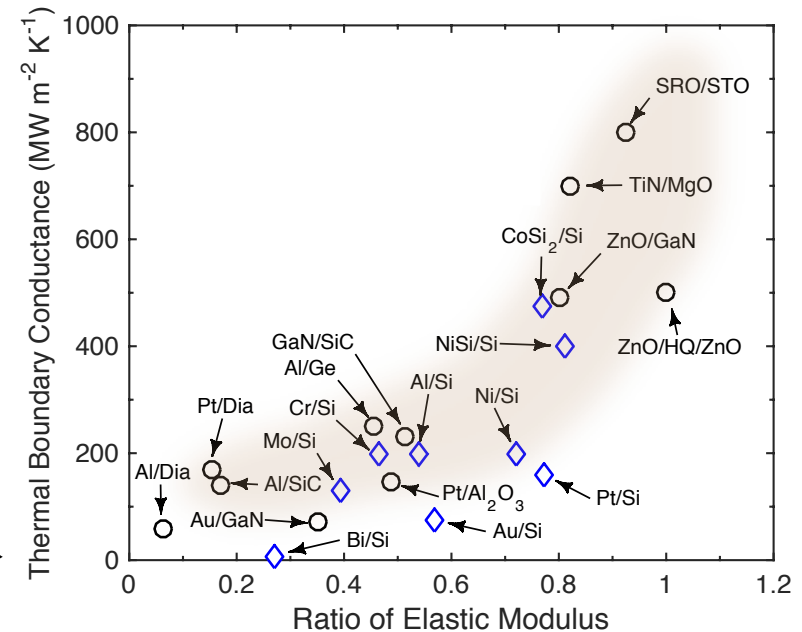
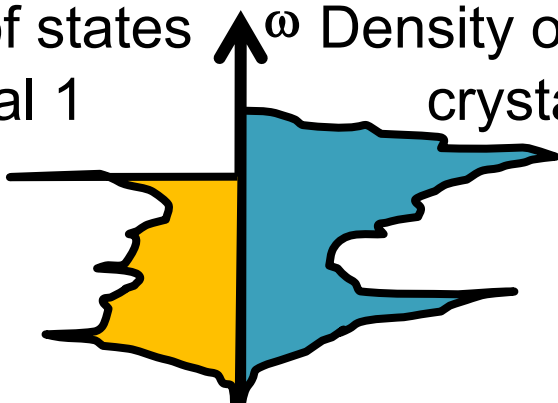
The basic traditional concept: phonon spectrum matching

$$h_K \propto \int_{\omega} C_{\omega} v_{\omega} \zeta_{\omega} d\omega \propto \int_{\omega} \hbar \omega D_{\omega} \frac{\partial f_{\omega}}{\partial T} v_{\omega} \zeta_{\omega} d\omega$$

Mismatch Models

Density of states
crystal 1

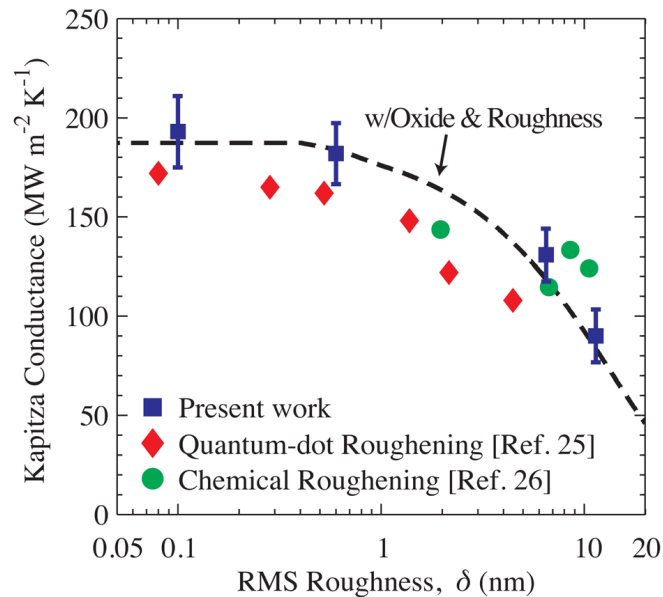
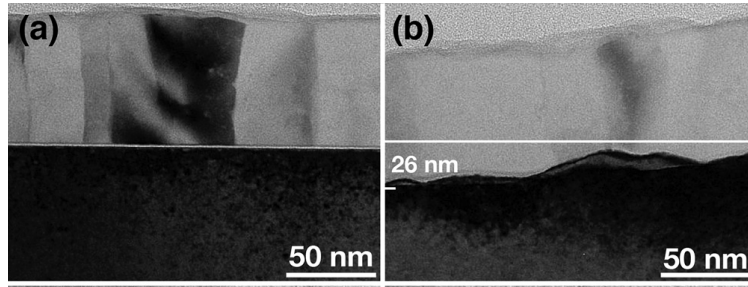
Density of states
crystal 2



Need “high quality” crystalline interfaces to compare to/validate/verify theoretical concepts

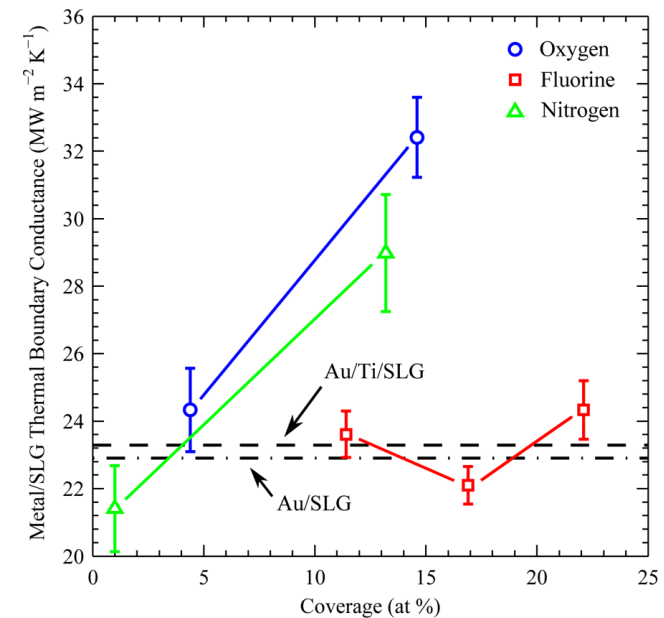
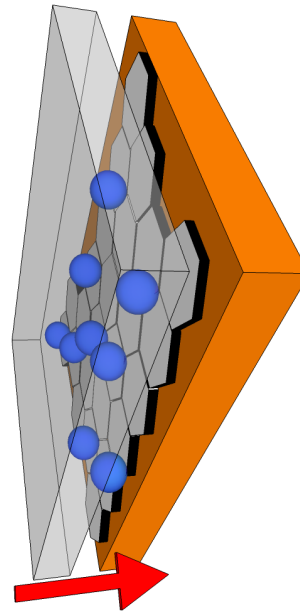
Interfacial imperfections can change in intrinsic TBC

Ex: Al/Si – roughness and native oxide



Duda & Hopkins, *Appl. Phys. Lett.* **100**, 111602 (2012)

Ex: metal/graphene – chemical functionalization



Hopkins *et al.*, *Nano Lett.* **12**, 590 (2012)

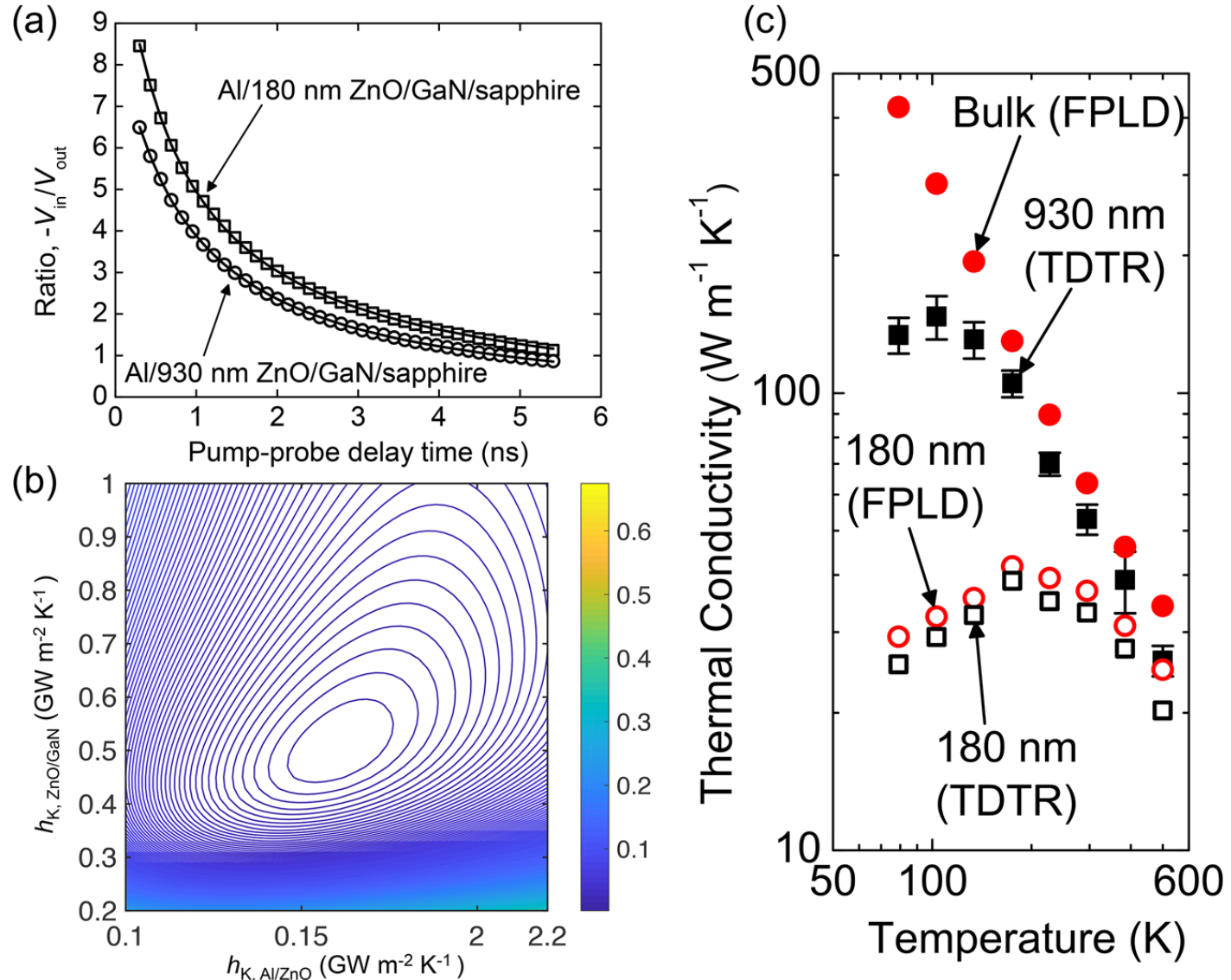
Foley *et al.*, *Nano Lett.* **15**, 4876 (2015)

Walton *et al.*, *Surf. & Coat. Tech.* **314**, 148 (2017)

Previous work on “epitaxial” interfaces – and our study

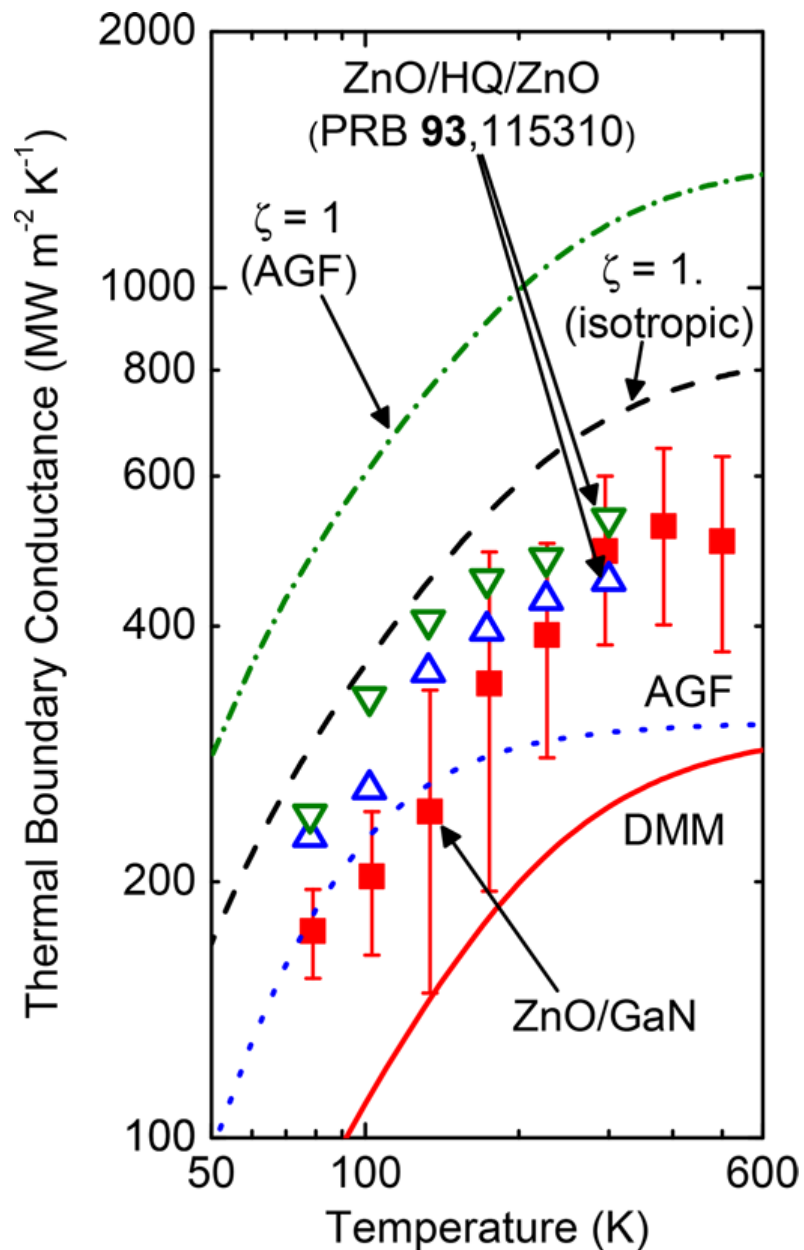
- Need “high quality” crystalline interfaces to compare to/validate/verify theoretical concepts
- Previous “epitaxial” interfaces are metal/non-metal
 - Ex: Bi/Si (Horn-von Hoegen)
 - Ex: TiN/MgO (Cahill)
 - Ex: SrRuO₃/SrTiO₃ (Cahill)
 - Ex: Silicide/Si (Feser, Fisher, Janotti)
- **Our Goal:** Use TDTR to measure TBC across heteroepitaxially grown ZnO on GaN substrates
- *Nearly* ideal interface to study in tandem with theoretical models (DMM, AGF)
- Gaskins *et al.* *Nano Letters* **18**, 7469 (2018)

TDTR measurements – uncertainty and layer properties

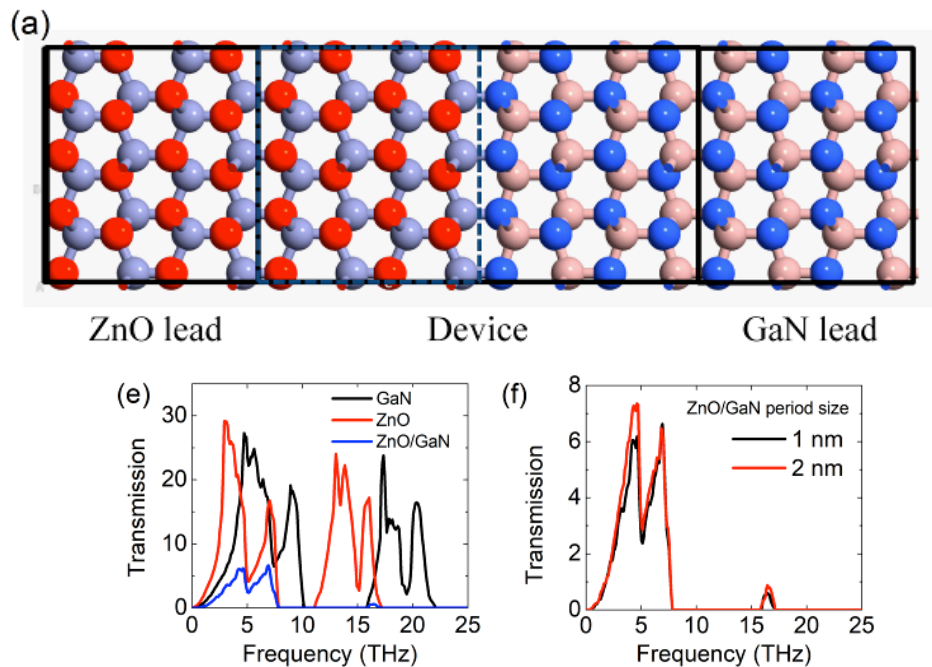


Gaskins *et al.* *Nano Letters* **18**, 7469 (2018)

TBC across ZnO/GaN interfaces

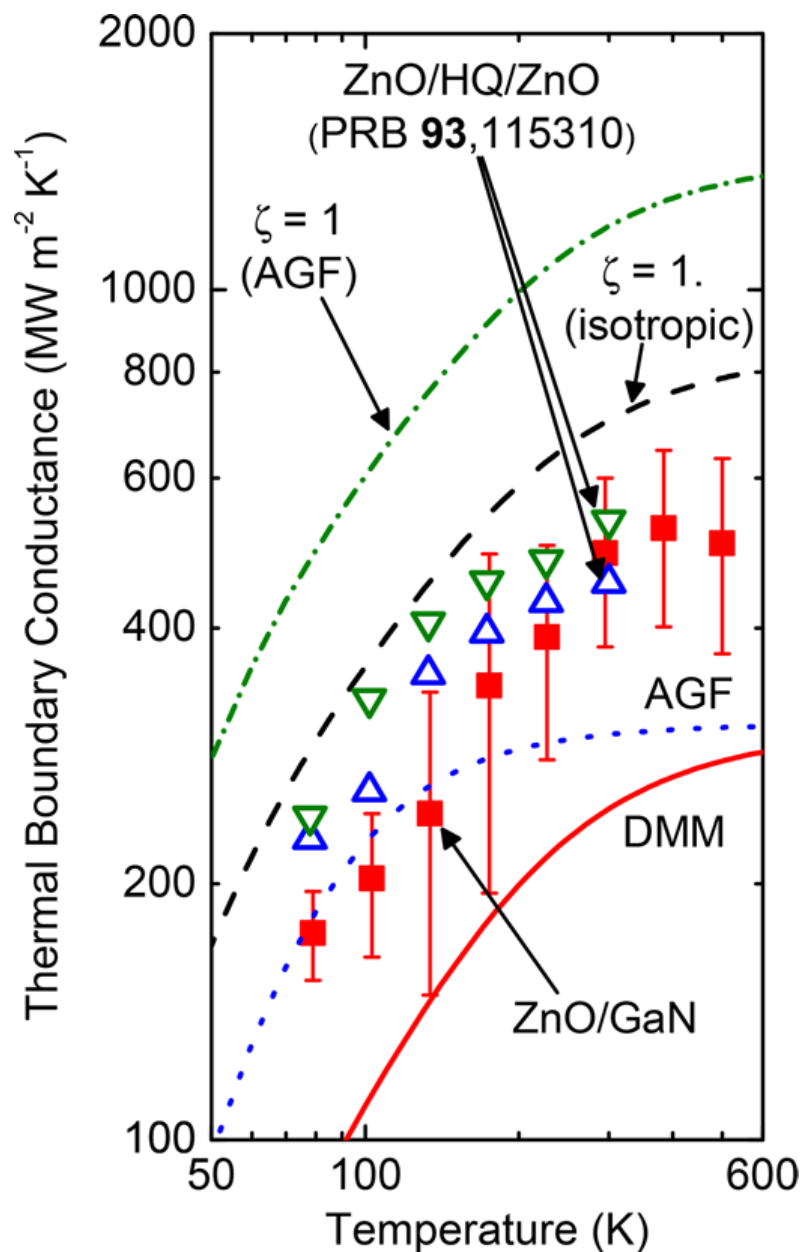


Elastic DMM and AGF can not capture high temperature TBC measurements (calcs from J. Shiomi and A. Henry)

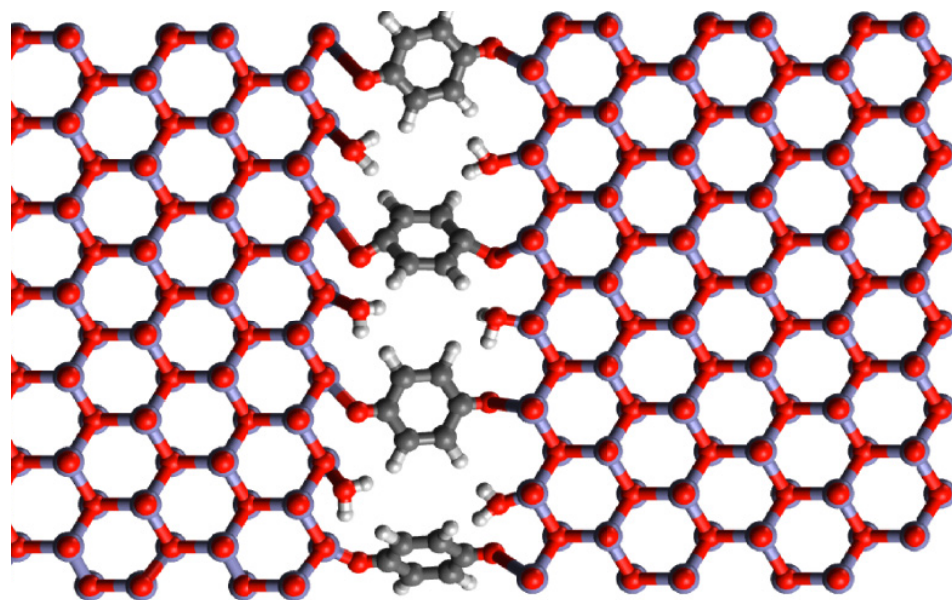


Gaskins *et al. Nano Letters*
18, 7469 (2018)

TBC across ZnO/GaN interfaces

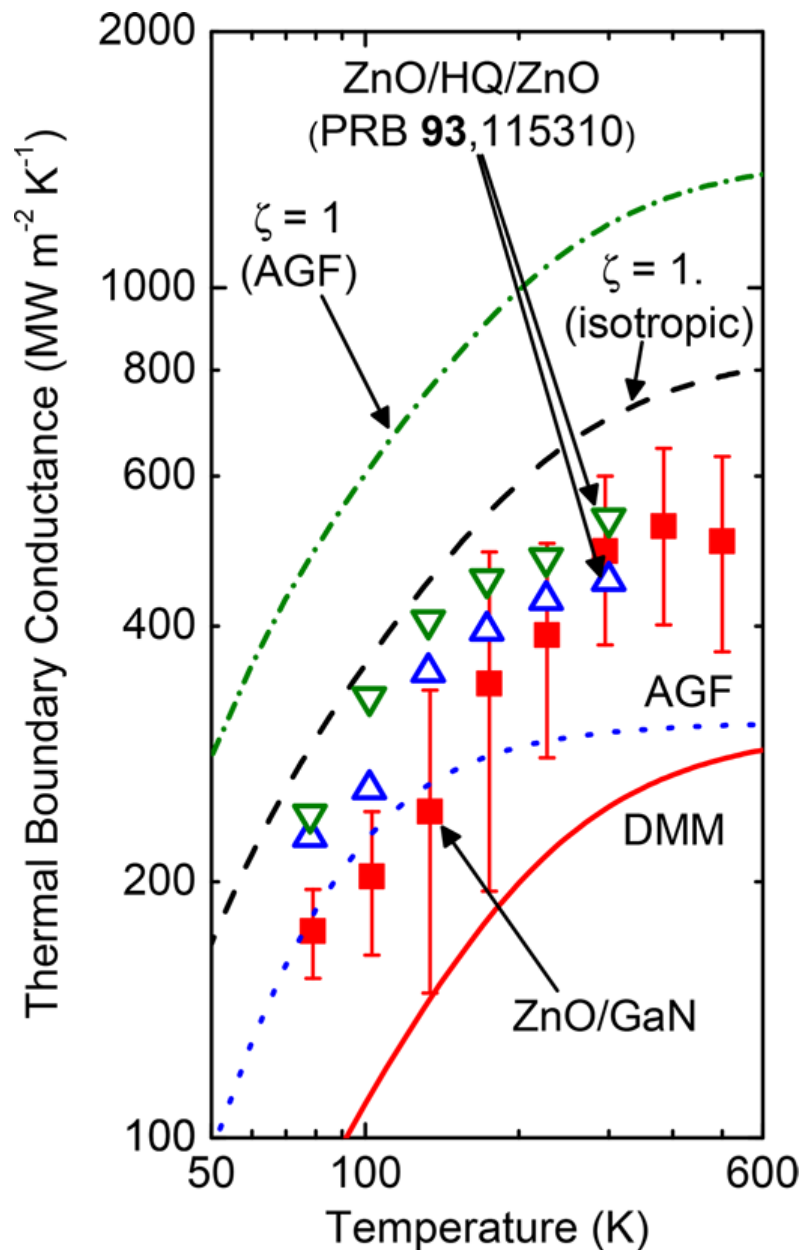


ZnO/GaN TBC similar to ZnO/HQ/ZnO TBC demonstrating upper limit to diffusive scattering

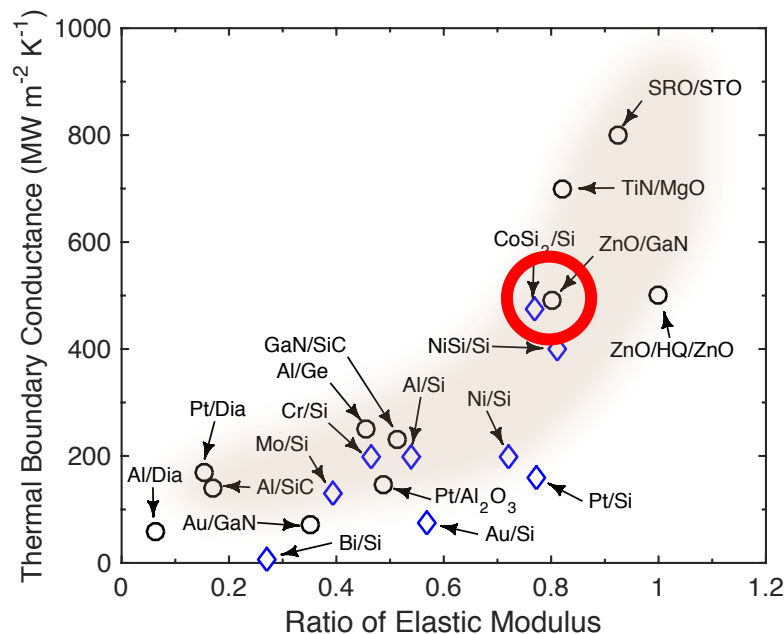


Gaskins *et al. Nano Letters*
18, 7469 (2018)

TBC across ZnO/GaN interfaces



ZnO/GaN TBC highest TBC for crystalline/crystalline non-metal/non-metal to date

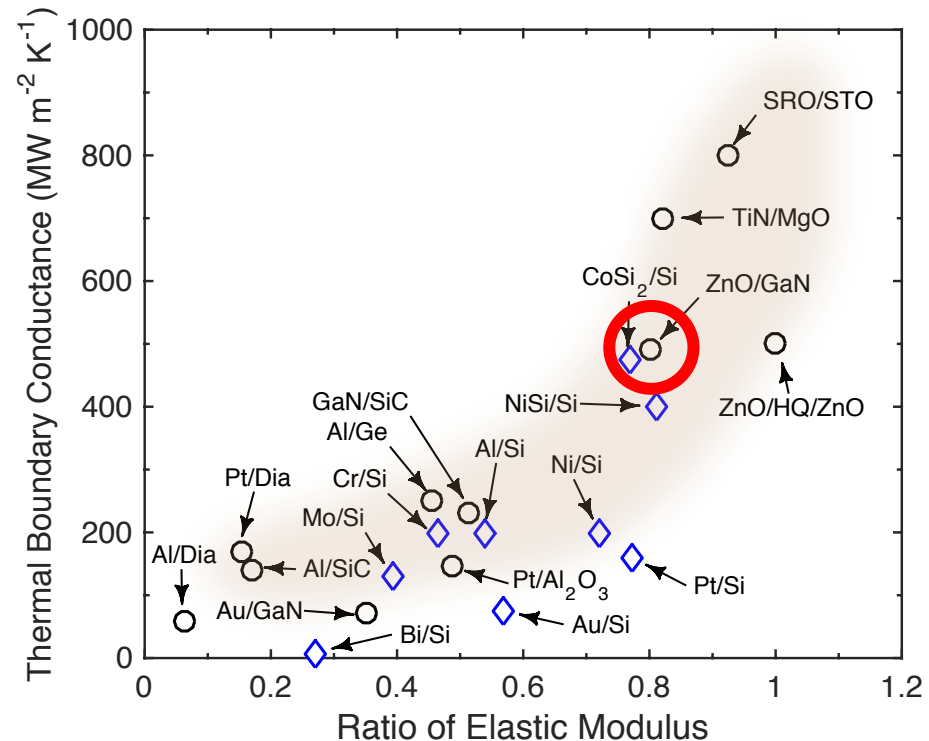


Gaskins *et al. Nano Letters*
18, 7469 (2018)

Conclusions

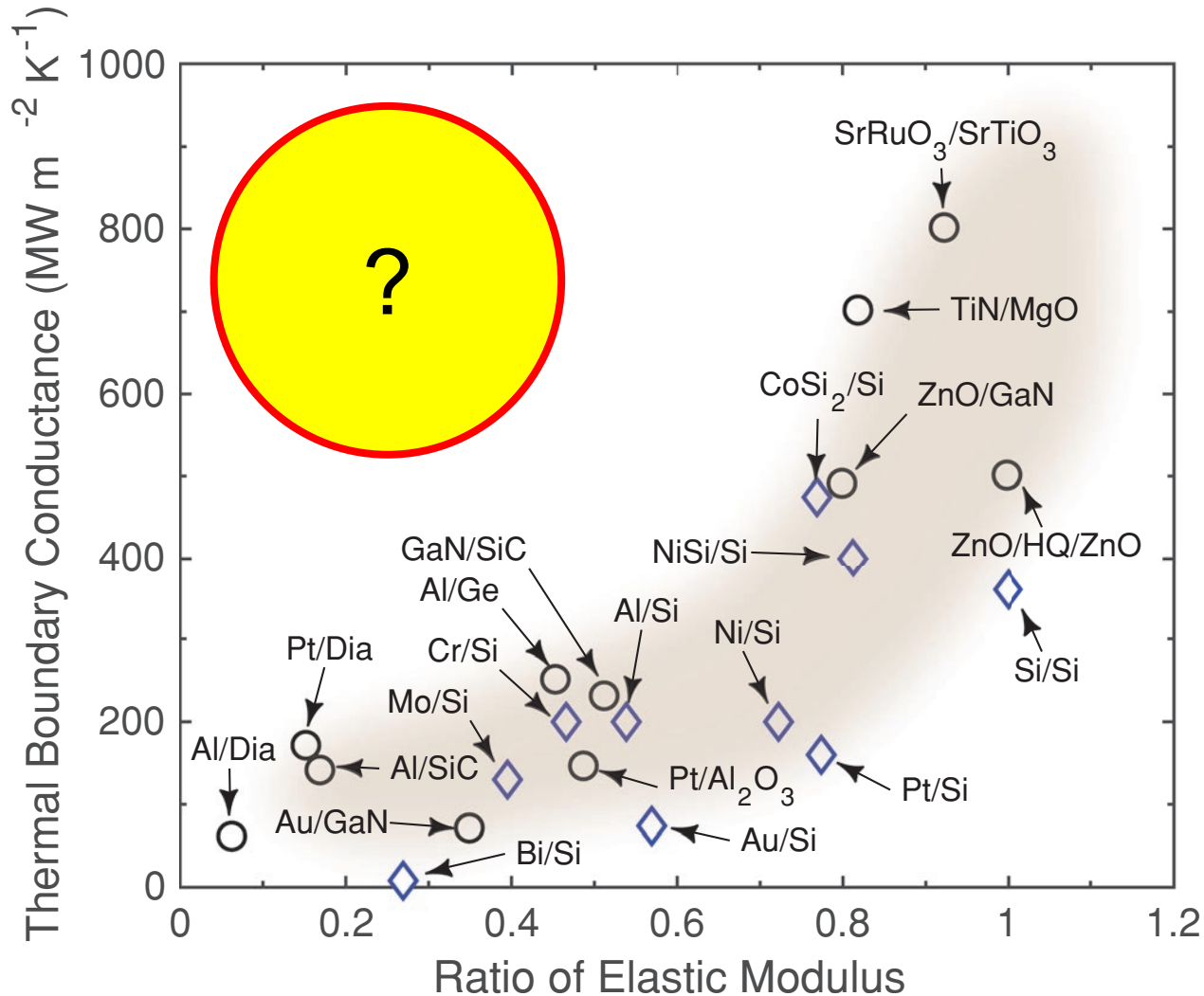
Gaskins *et al. Nano Letters* **18**, 7469 (2018)

- ZnO/GaN TBC highest TBC for crystalline/crystalline non-metal/non-metal to date
- Elastic models (semi-classical and atomistic) fail to capture high temp values
- Inelastic scattering? Interfacial modes? Robust landscape of directions can be explored with high quality, well controlled interfaces

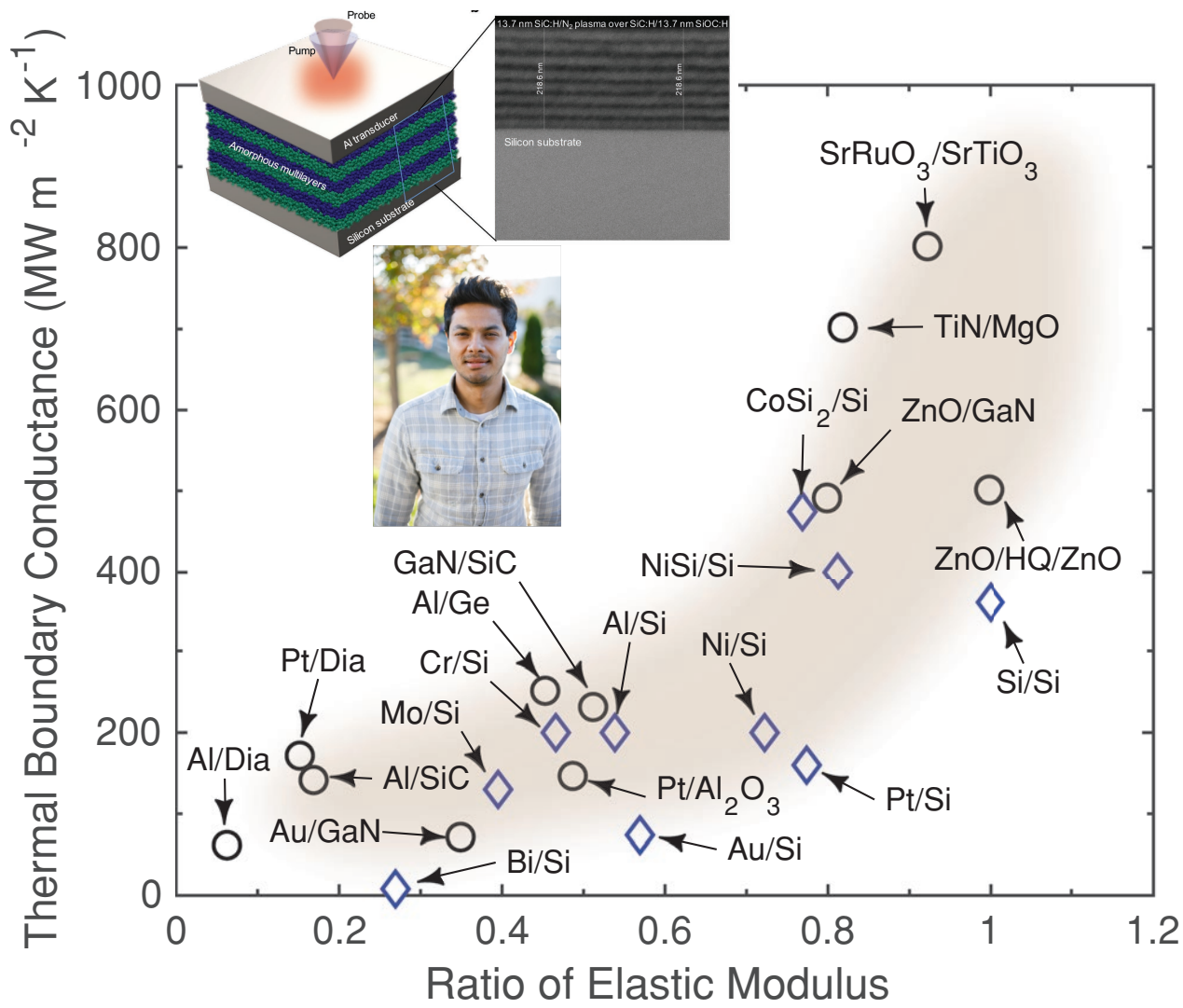


Looking ahead

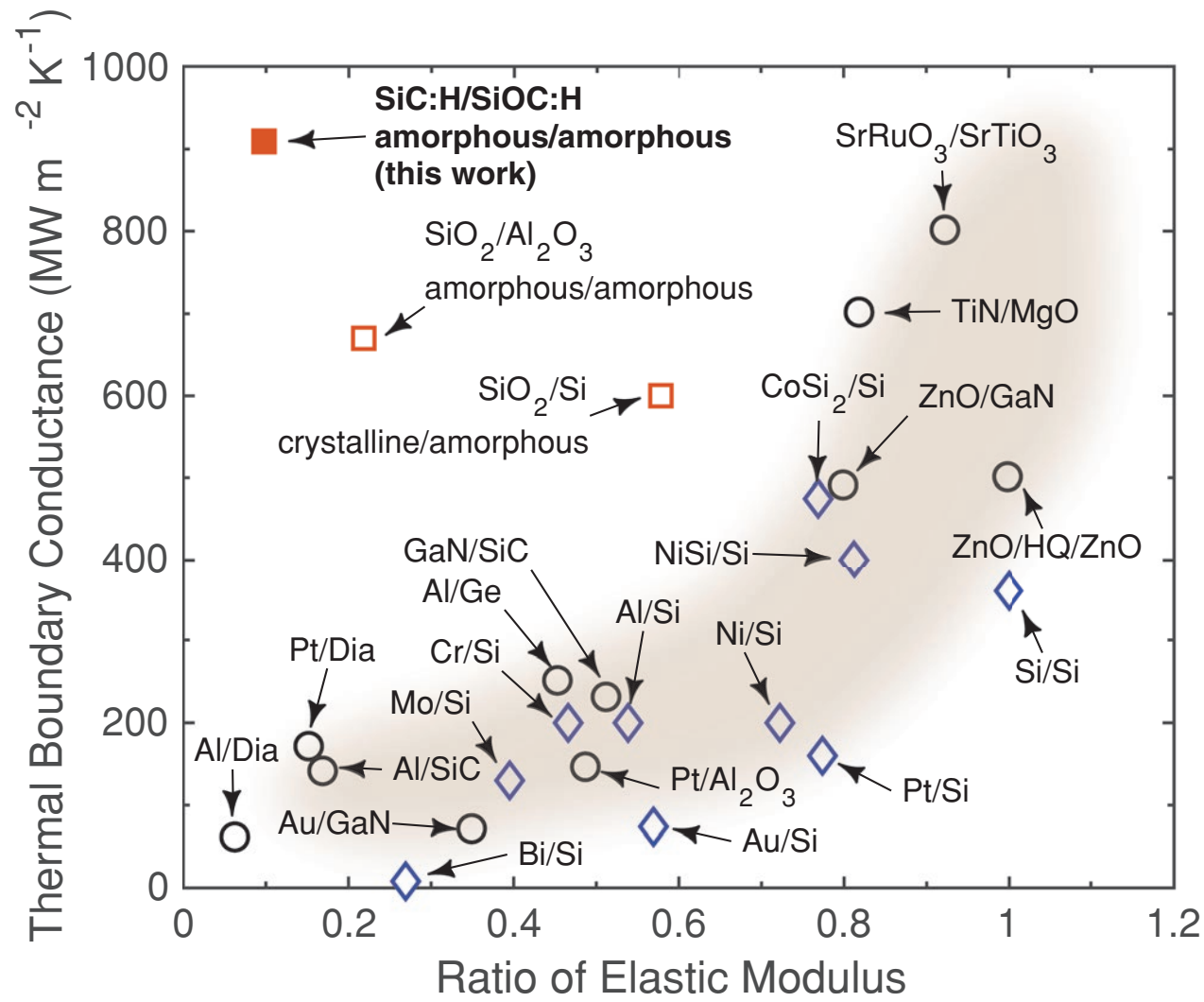
Giri *et al.* *Advanced Materials* **30**, 1804097 (2018)



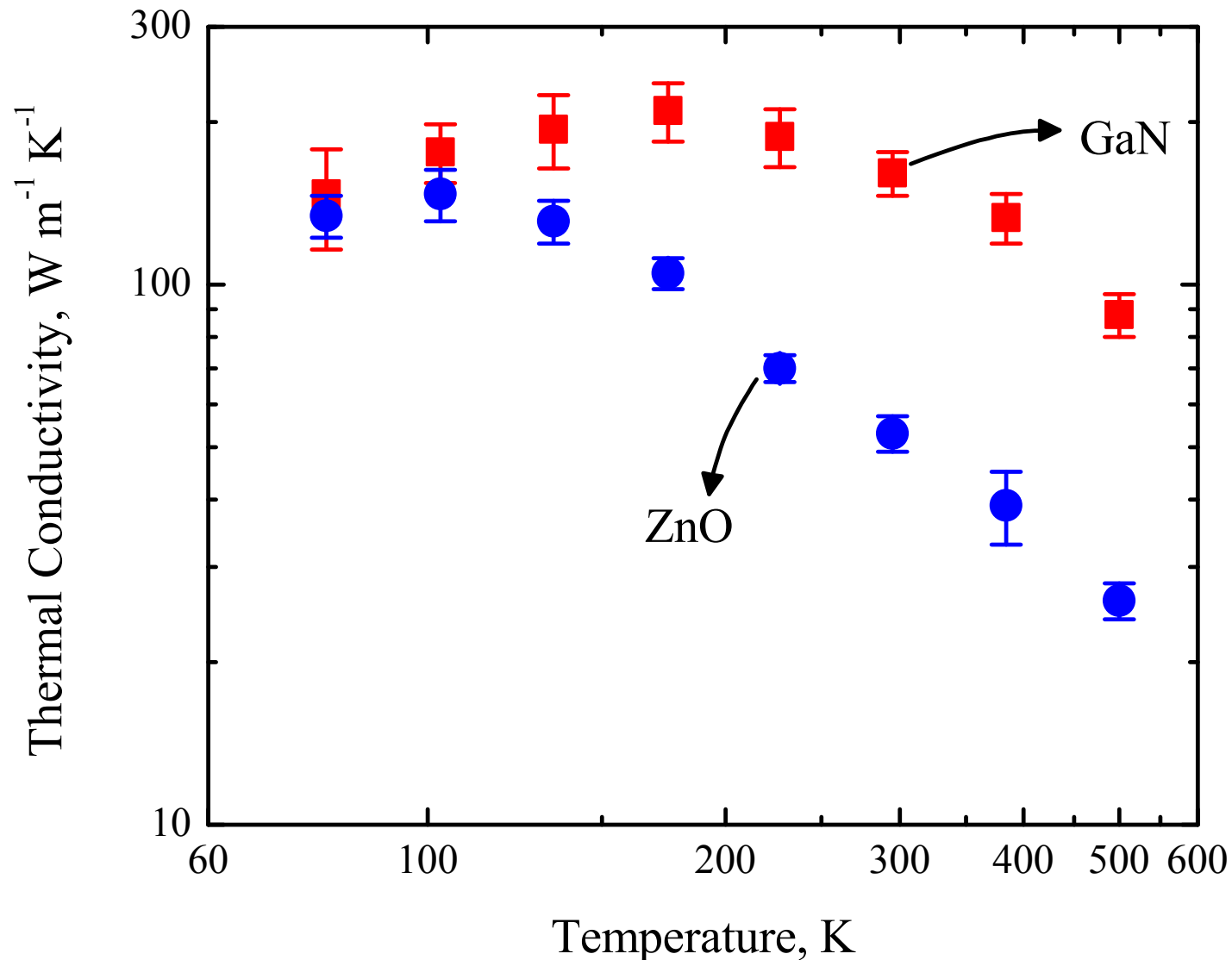
Giri et al. *Advanced Materials* **30**, 1804097 (2018)



Giri *et al.* *Advanced Materials* **30**, 1804097 (2018)

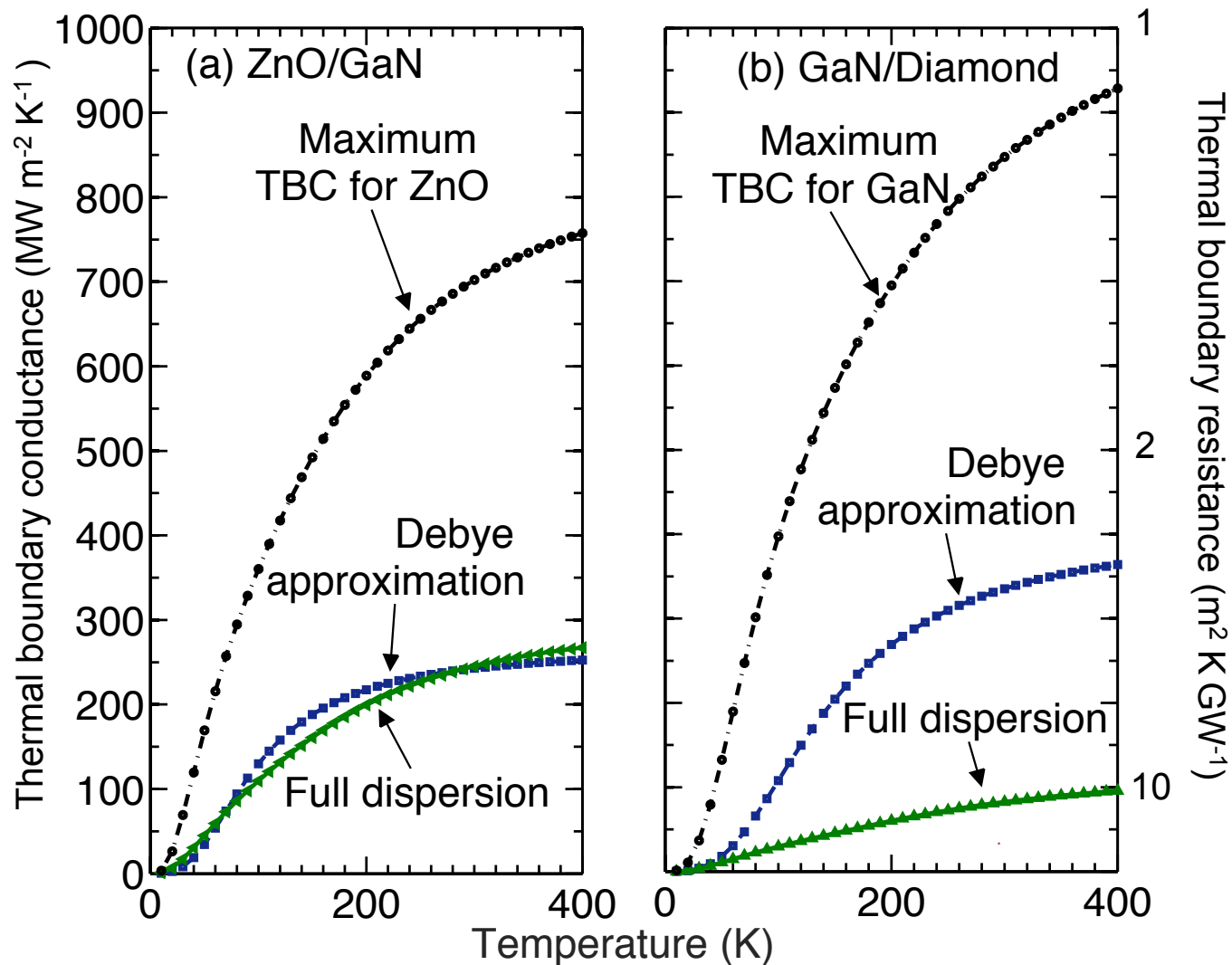


Thermal conductivity of GaN film on sapphire



Gaskins *et al. Nano Letters* **18**, 7469 (2018)

In DMM calcs, should use full dispersion



Gaskins *et al.* *Nano Letters* **18**, 7469 (2018)

ZnO and GaN dispersion assumptions

